UNITED STATES PATENT AND TRADEMARK OFFICE **CERTIFICATE OF CORRECTION**

PATENT NO.

: 6,850,244 B2

Page 1 of 1

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INVENTOR(S) : Aaftab Munshi and Colin Sharp

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Title page,

Item [73], Assignee, reads "Micron Techology, Inc.," should read -- Micron Technology, Inc., --.

Column 2,

Line 42, reads "values that may be unequal that are used" should read -- values that are used --.

Column 4,

Line 7, reads "detailed below," should read -- detail below, --.

Column 6,

Line 32, reads "D = (fu * Pu * scaleu) + (fv * Pv * scalev)," should read -- D = (fu * Pu * scale_u) + (fv * Pv * scale_v), --. Line 41, reads "values scaleu and scalev" should read -- values scaleu and scalev --.

Signed and Sealed this

Sixteenth Day of August, 2005

JON W. DUDAS

Director of the United States Patent and Trademark Office